INSTRUMENTAL ANALYSIS

SHAAS N HAMDAN

1st Lab: Rock Thin Sections

Tools & instrument:

- 1. petrographic glass slides
- 2. Cover slip & Epoxy (to put the cover)
- 3. Diamond saw (cutting machine to cut rock slab)
- 4. lap for grinding & a small warming plate
- 5. coarse, medium, & fine carbide grit powder (about 400, 800, & 1200) to polished rock slab
- 6. Automatic grinding machine to complete the polishing of the rock slab
- 7. Microscope (To ensure the accuracy of work)
- 8. Hot plat (Electric gas)
- thin section preparation is needed in order for samples to examined microscopically in order to analyses the characteristics of the soil or rock
- This analysis is normally carried out using transmitted polarised light which creates a need for thin sections of known & exact thickness

• Experience & steps

- 1. Cut the rock slab on the Diamond saw
- Start the polish by carbide on the granding machine to make the surface smooth, and then uses the glass disk and the carbide (400-600mm) & (800mm) to complete the polishing
- 3. put slab on the Hot Plate with the slide to get off the pebbles from the slab
- 4. While the rock slap on the Hot Plate, put on it the Like Side to stick the slab on the slide
- 5. put the slide on the slab by angle of 45°
- 6. put the slide on the Automatic granding machine to decrease the thick of the slab
- Repeat the polish on the disk of the glass & look under the microscope to see the grains if it need more polishing or not
- 8. use the Epoxy to stick the cover

Thinsections: 0.03mm, 30µm

Cover Slip Epoxy Epoxy Epoxy Glass Slide

2nd Lab: Rock Staining

I. Tools & instrument:

- The samples cut & polished before staining, Size is a personal preference, the only restriction being the ability to fit it within the containers being used for staining
- If the saw uses an <u>oil coolant</u>, wash off the excess oil from the slab with water

Staining inv	Staining involves the use of 3 chemicals			
Hydrofluoric	To etch the polished surface,			
Acid (HF)	breaks bonds between K, Ca			
Amaranth	Powder to stain plagioclase on			
$C_{20}H_{11}N_2Na_3O_{10}S_3$	surface in a red color			
Sodium -	To stain any K-feldspar on that			
Cobaltinitrite	surface a yellow color			

- As Use HF: use resistant apron, gloves, & eye protection goggles when handling it
- 33HF/500ml water
- 20%Na₃CO(NO₂)₆ \rightarrow 20g/100ml water

III. Experience & steps

1. Dip polished face into the HF (1min), & then Rinse it (5-10 s)

نعمل Polishing للصخر ثم نعرضه لحمض HF لمدة 3د (تعتمد المدة على حجم العينة) ونغسل الصخر جيدا بعد تعريضه للحمض

 Dip the same face into the Amaranth solution for approximately 2-5 sec & then rinse it & you'll see that the plagioclase are staining in red color

نأخذ العينة ونضعها في Amaranth وهي مادة عضوية تؤثر فقط على البلاجيوكليز من دقيقتين الى ثم نغسلها والنتيجة سنرى مناطق تلونت في

اللون الاحمر وهي بلورات ال plagioclase

3. Dip the same face of the slab in the same manner, in Sodium Cobalt nitrite for 1min, & then Wash the sample, The K-feldspar should be stained a yellow color

بعد ان تجف العينة نغمسها في الصوديوم كوبالتنايتريت نغسل العينة ونلاحظ انه ظهر لون اصفر بها وهو صبغة الفلدسبار

4. Quartz & ferromagnesian will remain unstained & in their original color

والمعدن الذي لا يتأثر بهذه الصبغات هو الكوارتز فيبقى لونه ابيض او سكني وايضا ال ferromagnesian والتي تبقى سوداء

5. Optional. protect it by spraying on a thin film of clear plastic



Yellow is the K-feldspar staining by Na-Cobaltinitrite Red is the Plagioclase staining by Amaranth C20H11N2Na3O10S3 Gray & White is the quartz (don't stained) Black is ferromagnesian minerals

Granite rocks

3rd Lab: Rock Preparation

- Preparation: crush the rock into small species to separate the minerals (Eg. Hornblend, & plagioclase from Gabbroic Hornblendite rock)
- Decanting: sample washing, after crushing the sample should be washed to remove dust
 sieving: separate the

sample into different

size



- A separated mineral is required for optical study, X-ray diffraction, & chemical analysis
- The method of separation depends on amount of separated mineral & grain size of the mineral
- To separate minerals (sieves), grain size must be < 250µm because the grain of this size made up of one mineral (>250 may be > one mineral)

Tools & instrument:

1. jaw crusher: to crush builders into species



- 2. **Ring Mill:** to crush rock fragments into powder for wet chemical analysis or sand & silt size (less time) for separation
- 3. Electrical grinding machine (the Agate mortar): crush rock fragments into powder

Experimental Procedure:

- 1. Use the jaw crusher to crush builders
- put these rock species into the Electrical grinding machine (the Agate mortar) or Ring Mill to crush it into a powder
- 3. Put the crushed sample into the sieves to separate the sample into different size
- 4. Decanting (washing) the crushed & sieved grains to remove dust

4th Lab: Mineral Separation

- **Separation:** Separate minerals after crushing & sieving depending on the physical properties
- We can separate any mineral by 2 Ways: magnetic separation & using Heavy liquids
- All minerals can be classified into 3 groups:

Group	Definition
Ferromagnetic	Have constant magnetic properties, regardless they are exposed to an external field
Diamagnetic (Repelled)	don't have magnetic properties unless it's exposed to an external field
Paramagnetic (attached)	(repelled or attached to a magnetic field)
Group	Separated using
Ferromagnetic	Hand-magnet
Diamagnetic	FIMS to separate it from para. & then using heavy liquids
Paramagnetic	FIMS

- The Frantz isodynamic magnetic separator FIMS: incorporates an electromagnet with 2 elongate pole pieces arranged, space between the poles is much wider on one side than other
 - Mineral particles are introduced into the upper end of chute & slide toward the lower
 - At the lower end the particles are separated to 2 streams, higher & lower susceptibility
 - Metal with higher susceptibility move toward the side of the chute where the pole gap is narrow & magnetic flux greatest
 - Side slope: 20°, Tilt: 5° (low susceptibility) & 15° (moderate to high susceptibility)
 - The way in which mineral separate as they move along the length of chute depends on:
 - 1. chute tilt, & slope & rate of feed to the chute
 - 2. amperage applied to be electromagnet
- if we put minerals in a liquid, the mineral with more density than liquid will fall down

Common heavy liquids				
Bromoforn	2.85 g/ml			
Tetrabrom	oetha	ane		2.96 g/ml
Diiodomet	hane			3.32 g/ml
		Granite Co	omposition	
Para		I [A]	Dia	ρ[g/cm³]
Biotite		0.8	Feldspar,Qz	< 3.0
Monazite		0.6	Apatite	3.1
			Zircon	4.56
0.4A	0.8A		1.5A	1.5A
Garnet	Biot	ite	Muscovite	Zircon
Ilmenite	Hori	nblende	Spinel	Rutile
Chromite	Нур	ersthene	Enstatite	Titanite
Chloritoid	Chlo	orite	Tourmaline	Apatite
Olivine	Aug	ite	Zoisite	Corundum
	Actinolite		Diopside	Barite
	Staurolite		Tremolite	Fluorite
	Epid	lote		Sillimanite
				Kyanite



Generation of X-rays (K-Shell Knockout)

Electrons in a higher orbital falls to the lower energy level, releasing its extra energy in the form of a photon. It's a big drop, so the photon has a high energy level; it is an X-ray photon



The free e- collides with the tungsten atom, knocking e- out of a lower orbital. A higher orbital e- fills the empty position, releasing its excess energy as a photon

- Absorption of X-rays
 - A larger atom is more likely to absorb X-ray because larger atoms have greater energy differences between orbitals (energy level more closely matches the energy of photon)
 - Smaller atoms, where the e- orbitals are separated by relatively low jumps in energy, are less likely to absorb X-ray photons
 - The soft tissue in your body is composed of smaller atoms, & so does not absorb X-ray photons particularly well. Ca (in bones) are much larger, so they are absorb X-ray
- Diffraction: wave phenomenon in which the apparent bending & spreading of waves when they meet an obstruction

- Diffraction occurs with EMR such as light & radio waves, & in sound waves & water waves
- Ex. double-slit diffraction, that's why firstly we remember light diffraction
- LIGHT DIFFRACTION: caused by light bending around the edge of an object
 - The interference pattern of bright & dark lines from the diffraction experiment explained by the additive nature of waves
 - wave peaks add together to make brighter light, or a peak & a through will cancel each other out & result in darkness





- **Single particle:** To understand diffraction we have to consider what happens when a wave interacts with a single particle. The particle scatters the incident beam uniformly in all directions
- Solid material: If we consider a crystalline material, scattered beams add together in a few directions & reinforce each other to give diffracted beams



• Diffraction of Waves by Crystals

- The structure of crystal determined by studying the diffraction pattern of a beam of radiation incident on the crystal
- > Beam diffraction in a certain specific directions
- By measuring the directions of the diffraction & the corresponding intensities, one obtains information concerning the crystal structure responsible for diffraction



- X-RAY CRYSTALLOGRAPHY: technique in crystallography in which the pattern produced by the diffraction of x-rays via closely spaced lattice of atoms in a crystal is recorded & then analyzed to reveal the nature of that lattice
- X-Ray Diffraction XRD
 - W. L. Bragg presented a simple explanation of the diffracted beams from a crystal.
 - The Bragg derivation is simple but convincing only since it reproduces the correct result
 - W.H. Bragg & his son W.L. Bragg developed a relationship to explain why the cleavage faces of crystals appear to reflect X-ray beams at certain θ of incidence, & This observation is an example of X-ray wave interference "analysis of crystal structure by means of X-rays"
- Bragg Equation: identifies angles of the incident radiation relative to the lattice planes for which diffraction peaks occurs
 - Bragg derived the condition for constructive interference of the X-rays scattered from a set of parallel lattice planes
 - W.L. Bragg considered crystals to be made up of parallel planes of atoms. Incident waves are reflected specularly from parallel planes of atoms in the crystal, with each plane is reflecting only a very small fraction of the radiation, like a lightly silvered mirror
 - The diffracted beams are found to occur as the reflections from planes interfere constructively
 - We treat elastic scattering, in which the energy of X-ray is not changed on reflection
 - In mirror like reflection the angle of incidence is equal to the angle of reflection



The diffracted beams (reflections) from any set of lattice planes can only occur at particular angles predicted by the Bragg law

Diffraction maximum (diffractograph)

- Coherent scattering from a single plane is not sufficient to obtain a diffraction maximum. It is also necessary that successive planes should scatter in phase
- This will be the case if the path difference for scattering off 2 adjacent planes is an integral number of λ



6th Lab: X Ray Fluorescent (elemental analysis)

- Accuracy: is how close a result to the true value
 - Determining the accuracy of a measurement usually requires calibration of the analytical method with a known standard
- **Standards**: Materials containing a known concentration of an analyte
 - They provide reference to determine unknown concentration & calibrate analytical instrument
- Precision:reproducibility of multiple measurement



- described by the standard deviation, standard error, or confidence interval
- X-ray fluorescence: emission of characteristic secondary X-rays (fluorescent) from a material that excited by bombarding with high-energy X-ray or v
 - used for elemental & chemical analysis (in the investigation of metals, glass, ceramics, & building materials), research in geochemistry, forensic science, & archaeology
- Electronic orbitals: Each element has electronic orbitals of characteristic energy,Following removal of inner e- by an energetic photon provided by a primary radiation source, an electron from an outer shell drops into its place





2) An electron from the L or M shell "jumps in" to fill the vacancy. In the process, it emits a characteristic x-ray unique to this element and in turn, produces a vacancy in the L or M shell.) When a vacancy is created in the L shell by either the rimary excitation x-ray or by the previous event, an electron rom the M or N shell "jumps in" to occupy the vacancy. In its process, it emits a characteristic x-ray unique to this lement and in turn, produces a vacancy in the M or N shell.



- In XRF spectrometer: X-ray photons are counted & their corresponding energies (kV) are measured. The resultant data set is displayed as a spectrum
- Moseley's law: relationship between atomic number (Z) & energy of emission lines for each specific X-ray line series (the Kα line or the Lβ line)
 E = a(z-s)2

Energy = constant (atomic# - constant of line series)

- Moseley's law indicates that element's spectral lines are smooth function of the atomic number
- The spectral lines for elements with low atomic number (light) occur at lower energies
- The peak energies & spectral group patterns provide for qualitative identification



- XRF is well-suited for investigation (advantages)
 1. bulk chemical analyzes of major element
 - bulk chemical analyzes of trace elements
 - 3. detection limits for trace elements are typically on the order of a few parts per million (ppm)
- Limitations (disadvantages)
 - > depending on λ & intensity of incident x-ray
 - Limited in ability to precisely & accurately measure abundances of element with Z<11</p>
 - cannot distinguish variations among isotopes
 cannot distinguish ions of the same element in different valence states





 الفرق بين coating & curving هو في الكوتنج ابقاء جميع المظاهر المورفولوجية واضحة



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Generation of Characteristic X-Rays

- Characteristic X-rays generated when an energetic beam of electrons interacts with the inner shell electrons by inelastic scattering with enough energy to excite inner shell electrons to outer shell orbitals, leaving inner-shell vacancies
- As outer-shell electrons fall to the various inner shell orbitals, characteristic amounts of energy are generated that are a function of the target element & the type of orbital decay
- Much of the energy is emitted from the atom or internally absorbed & knock out another outer shell electron (Auger electron) with additional energy emissions

	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18
1	Hydrogen		A	tomic —	. Դ				Alkali M	fletal a Earth	No	nmetal logen						He
2	Li	Be	Sj	mbol —	Нус	drogen	Na	ame	Transiti	on Metal letal	No	ble Gas	B H	C	N Nitrone	O	F	Nee Nee 201777
3	Na Sodam 22.96511828	Mg Mg Magneturi 21.335	A	tomic — Mass	1	.008			Semim	etal	Act	inide	Al Abarasian XX8115285	Si	P Peoplans NUTINISH	S Safar	S Cl Control Test	Ar Ar
4	Associates TRONG	Ca	Scandian ALSESSEE	P Ti Toelon Calo	V V Veradian Sci.Seci.S	Cr Crossian SLIMI	Mn Mn Narganese Sci 2004	Fe	Coball	Ni Ni	Cu	[°] Zn	Ga	Ge	As Assess	Se	Br	Kr Kr
5	Rb	Strustan U/A2	Y Yrzan M.Hostel	Zr Zressium 51.224	Nobian Nobian Nobian	Mo Mo No/denum	Tc Tc	Ru Ruberian 101.87	Rh	Pd Pd Paladian 19642	Ag	Cd Cdesan Lizzat	In	Sn	Sb Attenty 12136	* Te	Lines I	Xe
6	CS Canvian INTERSPECTOR	Ba	57-71	+ Hf	Ta tatelor tatelor	Tungether 20124	Re Besium 156.227	Osvian 19423	bidium 192.217	Pt	Au Sold States	Hg	TI Tutter XLB	Pb Ba	Bi	Po	At	Rn Index
7	Fr Instan	Ra	89-103	Rf References	Db 3	Sg	Bh Botrium 271	Hashen Bashen 250	Mt Meterium 278	Ds Darmstadtium 281	Rg	Coveridue 285	Nh	Fl	MC	LV Denotan Si	TS TS	Og ogunan N

8th Lab: Microprobe analysis

Electron probe micro-analyzer (EPMA) (-RAY **Electron Column** Sample Chamber analysis *Microp* Secondary Intensity robe **Electron Detector** EPMA Backscattered Electron Detector -RAY for lavelength-Dispersive inalysis Spectrometers WDS Visible-Light Microscope Thinsection Such XRF **Energy-Dispersive Spectrometer**

- 1. **Gun:** electron source (W-filament cathode)
- 2. Electromagnetic lenses: condense & focus the electron beam emanating from the source, located in the column of the instrument
- 3. sample chamber: prevent gas & vapor molecules from interfering with the electron beam, has movable stage (X-Y-Z), that is under a vacuum to
- **Detectors:** collect x-rays & electrons emitted. 4. around the sample chamber
- **Applications**
- Quantitative EPMA: the most commonly used 1. method for chemical analysis of geological & industrial materials at small scales
- 2. individual phases analyzed or small size or valuable
- 3. Used for analysis of synthetic materials (wafers, thin film, microcircuits, semi-conductors, ceramics)
- Strengths •
- 1. same instrument as an SEM, but differs by it is equipped with range of crystal spectrometer enable quantitative chemical analysis at high sensitivity
- primary tool for chemical analysis of solid at 2. small scales (<1–2micron diameter), spot analyses
- 3. Spot analyses obtained in situ, use to detect small compositional variations within textural context or within chemically zoned materials
- have an array of imaging detectors (SEI, BSE, & 4. CL) that allow the investigator to generate images of surface & internal compositional structures

Limitations (disadvantage)

- 1. Not detect light element (Atomic number Z<11)
- reported as oxides, not as cations 2.
- 3. cannot distinguish between the different valence states (oxidation number): e.g. ferric/ferrous ratio
- cannot distinguish different masses (isotopes) 4. .
 - User's **Guide-Sample** Collection & Preparation: Unlike an SEM, which can give images of 3D objects, analysis of solid materials by **EPMA** requires preparation of flat, & polished sections



any solid analyzed, samples prepared as standard-1. size 27x46 mm rectangular sections, or in 1-inch round disks

Rectangular sections are prepared as 30-micron 2. thicksections without cover slips, 1-inch cores can be polished, Chips or grains can be mounted in epoxy disks, then polished half way through to expose a cross-section of the material



- 3. The most critical step prior to analysis is giving the sample a fine polish so that surface imperfections don't interfere with electron-sample interactions. (important with different hardnesses; polishing should yield a flat surface of uniform smoothness)
- 4. samples are coated with a thin film of a conducting material (carbon C) & the coated sample surface put in electrical contact with holder
- Data Collection, Results & Presentation 2 methods of detecting & quantifying the spectrum of secondary X-rays emitted from the specimen



WDS (Wavelength-	EDS (Energy-dispersive
dispersive spectrometry)	spectrometry)
	By energy using a solid-
By λ , using a diffracting	state detector that
crystal to isolate the	discriminates between the
characteristic X-ray peaks	energies of incoming
	photons
High spectral resolution	Low spectral resolution
(element clearly resolved)	(deconvolute overlapping
	peaks)
Higher peak/background	
(better detection limits)	Lower peak/background
	(lower precision)
Sequential measurement of	Simultaneous collection of
peaks, slower	whole spectrum, rapid
	Insensitive to specimen
Specimen flat & in focus	geometry

No moving parts, & Less

expensive

الفرق بينه وبين WDS هو انه

يعطى التحليل لكل العناصر مرة

Specimen flat & in focus

Delicate moving parts

Expensive to buy مثل ال XRFلکن حجمه ص

- Samples & standards: The net intensity of the characteristic X-ray peak is proportional to the mass concentration of that element in the specimen
 - <u>quantitative</u> analysis relies on comparing the specimen with standard of the element
 - The standards are natural or synthetic materials with accurately known composition, either because they pure stoichiometric compound, or analyzed carefully by other techniques
 - Spot analysis, Profile analysis, Map analysis
 - Al₂Si₃O₁₂ PyropeMg₃,AlmandineFe₃,Spessartin Mn₃,GrossularCa₃,AndraditeCa₃Fe₂Si₃O₁₂



Chemical Analysis

- Reading chemical data
 - SiO₂, Al₂O₃, Fe₂O₃, TiO₂, Cr₂O₃, FeO, MnO, MgO, CaO, BaO, Na₂O, K₂O, F, Cl
 - ➤ The unit of wt% is gram_{oxide}/gram_{mineral}
 - Methods of analysis (major elements)
 - > Wet chemical: chemistry class stuff
 - Electron probe: fairly common, moderately easy, microscopic, highly precise & accurate
 - SEM EDS: here in building, easy, fairly precise & accurate, microscopic
 - XRF (X-ray fluorescence): whole-rock chemistry, very common, very easy
 - > Others: both whole-rock, & microanalysis

• Mineral Formulas

- minerals must have a well-defined composition
- The composition range of a mineral expressed by a general chemical formula
- formulas for different minerals are written with different numbers of oxygen's, because elements or groups will turn out to be integers
- To Calculate a mineral formula from the mineral analysis we're given (the feldspar analysis which contain 80
 - ➢ general formula: (Ca , Na , K)(Fe, A1, Si)₄O₈
 - Step 1: Moles of oxide
 - Step 2: Normalize Oxygens
 - Step 3: Calculate Cations
 - Step 4: Allocate cations to sites

$K_{0.030}Na_{0.582}Ca_{0.394}Al_{1.365}Si_{2.626}O_8$

يستخدم به polishing ويجب عمل polishing له وان يكون flat بسبب ان الاشعة يجب ان تنعكس وتعود لل detector فاذا كان هناك تعرجات يحدث لها تشوه، ويجب عمل coating في الكربون C لانه تحليل كيميائي لا يغطى بالمعادن ولان ال X-ray لا يستطيع تحليل للعناصر اقل من 11 ولان الكربون موصل للتيار الكهربائي الهدف منه هو تحليل كيميائي بمناطق صغيرة

الفرق الرئيسي بطرق التحليل الكيميائي Wavelength-dispersive spectrometry Energy-dispersive spectrometry

Step 1 - Moles of oxide					
	А	В	С		
oxide	weight percent (g oxide / g mineral)	Molecular weight (g oxide / mol oxide)	A / B (mol oxide / g mineral)		
SiO ₂	57.8	60.084	0.96		
AI_2O_3	25.5	101.961	0.25		
CaO	8.09	56.079	0.14		
Na ₂ O	6.61	61.9756	0.11		
K ₂ O	0.52	94.196	0.01		
Total	98.52				

Step 2 - Normalize O

	С	D	E
oxide	A / B (mol oxide / g mineral)	O per oxide (mol O / mol oxide)	C * D (mol O / g mineral)
SiO ₂	0.96	2	1.924
AI_2O_3	0.25	3	0.750
CaO	0.14	1	0.144
Na ₂ O	0.11	1	0.107
K ₂ O	0.01	1	0.006
Total			2.931

Step 3 - Calculate Cations

	С	F	G	Н
oxide	A / B (mol oxide / g mineral)	C * 8 / ΣE (mol oxide / mol mineral)	X ⁺ per oxide (mol cation / mol oxide)	F * G (mol cation / mol mineral)
SiO ₂	0.96	2.626	1	2.626
AI_2O_3	0.25	0.683	2	1.365
CaO	0.14	0.394	1	0.394
Na ₂ O	0.11	0.291	2	0.582
K ₂ O	0.01	0.015	2	0.030
Total				4.998

9th Lab: Spectroscopy

Atomic Absorption Spectroscopy (AAS) (elemental analysis such as XRF)

- **Spectroscopy**: use of the absorption, emission, or scattering of EM radiation to qualitatively or quantitatively study matter or physical processes depending on the distances between energy levels
- The matter can be atoms, molecules, atomic or molecular ions, or solids
- The interaction of radiation with matter can cause redirection of the radiation & transitions between the energy levels of the atoms or molecules

Spectroscopy	Transition	Transfer energy
Absorption	From lower to	From radiation
	higher level	field to absorber
Emission	From higher to	From the emitter
	lower level	to radiation field
Nonradiative	From higher to	No radiation is
decay	lower level	emitted
Scattering	Redirection of	May not include
	light due to its	emission (may
	interaction	have a different λ
	with matter	compared to light
		incident sample)

the type of transition that can occur when a photon in these spectral ranges interacts with matter *for energy levels split by a magnetic field

Type of Radiation	Frequency Range (Hz)	λ Range(m)	Type of Transition
gamma	10 ²⁰ -10 ²⁴	<1p	nuclear
X-rays	10 ¹⁷ -10 ²⁰	1n-1p	inner electron
ultraviolet	10 ¹⁵ -10 ¹⁷	400n -1n	
visible	(4-7.5)x10 ¹⁴	750nm400nm	outer electron
near- infrared	(1-4)x10 ¹⁴	2.5µm-750nm	outer electron molecular vibrations
infrared	10 ¹³ -10 ¹⁴	25µm - 2.5µm	molecular vibrations
microwaves	3x(10 ¹¹⁻¹³)	1mm - 25µm	molecular rotations, electron spin
radio waves	<3x10 ¹¹	>1mm	nuclear spin flips*



- Atomic absorption measures the amount of energy (in form of photons of light, & change in λ) absorbed by the sample
 - a detector measures the λ of light transmitted by the sample (after λ) compares to the λ,(before λ) which originally passed through the sample
 - A signal processor then integrates the changes in λ, which appear in the readout as peaks of energy absorption at discrete λ



هذه العمليات يفصل بين هذه العناصر

- To provide element specific λ, a light beam from a lamp whose cathode is made of the element being determined is passed via the flame (الكاثود مصنوع من الموع من العنصر الذي يجري له تحليل ليعطي نفس الطول الموجي)
- **Photonmultiplier** (detector): A device can detect the amount of reduction of the light intensity due to absorption by the analyte which directly related to the amount of the element in the sample
- Cathode lamp:
 - The hollow cathode lamp (HCL) uses a cathode made of the element of interest with a low internal pressure of an inert gas
 - The light is emitted directionally via the lamp's window, a window made of a glass transparent in the UV & visible λ





Atomic Cell

A. Burner تخرج منه ال flame باستخداه غازين الاستلين والاوكسجين

> B. Nebulizer يجعل العينة رذاذ

C. Rotational Adjust Knob

D. Horizontal Adjust Knob

E. Vertical Adjust Knob

Flame Atomizers

- A typical atomizer is a concentric tube nebulizer with a laminar flow burner
- The aerosol, which uses the oxidizer flow, is mixed with the fuel & passes a series of baffles which remove the larger mist & only passes the finer solution droplets
- The removal of the coarse mist means most of the sample is drained from the mixing chamber
- The aerosol-oxidant-fuel mixture are then combusted in a slotted burner that provides a flame from 5 - 10 cm in length
- Laminar flow burner provides quiet reproducible flame with a long path length
- **Types of Flames:** Several fuel & oxidant employed in flame spectroscopy depending on T needed
 - 1700 2400°C: various fuel when air (oxidant) only easily decomposed samples are atomized
 - Most common is oxygen or nitrous oxide (oxidant) with fuel Acetylene (2500 - 3100°C)

-		-	
Fuel	Oxidant	T(100°C)	Velocity(cm/s)
Gas	Air	17 - 19	39 - 43
Gas	02	27 - 28	370 - 390
H ₂	Air	20 - 21	300 - 440
H2	02	25.5 - 27	900 - 1400
Acetylene	Air	21 - 24	158 - 266
Acetylene	02	30.5 - 31.5	1100 - 2480
Acetylene	Nitrous	26 - 28	285

Monochromator: important device, separate the spectral line of interest from others spectral lines with different λ emitted by the hollow-cathode lamp



- > The desired spectral line is chosen with the preferred λ & bandwidth by an appropriate monochromator's setting named grating
- A grating is a reflective surface, scored either mechanically or holographically with parallel grooves that designed for different λ regions
- most of the instruments are equipped with 2 gratings with the goal to cover a λ range 189 851nm which is used in atomic absorption
- consists of the diffraction grating (dispersing element), slits, & spherical mirrors
- Beer-Lambert Law: linear relationship between absorbance & concentration of absorbing species مقدار الامتصاص للاشعة يتناسب تناسب طردي مع تركيز العنصر

$$\mathbf{A} = \mathbf{a} (\mathbf{\lambda}) * \mathbf{b} * \mathbf{c} = \mathbf{\varepsilon} * \mathbf{b} * \mathbf{c}$$

measured absorbance = $(\lambda$ -dependent absorptivity coefficient) * (path length) *(analyte concentration)

$$T = I / I_0$$

- Transmittance = light intensity after / initial intensity A = -log T = -log (I / Io)
- **Calibration Curves:** Atomic absorption follow Beer's law with absorbance being directly proportional to concentration

يستخدم لتحويل ال intensity of absorption ل concentration قبل ان نبدأ بعملية القياس نستخدم مجموعة standards تحتوي تركيز محدد معروف ثم نقيس ال absorption لهم ثم نعمللهم best line ونقيس ال absorption ونحدد نقطة ونقر أ تركيز ها

- لهذا فأنها عملية تحتاج وقت كثير فال XRF تستخدم أكثر منها departures from linearity are often encountered, & it is foolhardy to perform an atomic absorption analysis without experimentally determining whether a linear relationship exist
- A calibration curve that covers the range of concentrations found in the sample are prepared



- Linear regression uses the method of least squares to determine the best linear equation to describe a set of x & y data points
- The method of least squares minimizes the sum of the square of the residuals – the difference between a measured data point & hypothetical point on a line
- Residual squared, +ve & -ve value don't cancel
- Spreadsheets will often have built-in regression functions to find the best line for a set of data
- A common application of linear regression in analytical chemistry is to determine the best linear equation for calibration data to generate a calibration or working curve
- concentration of analyte in a sample can then be determined by comparing a measurement of the unknown to the calibration curve
- Linear Regression Equations

Test Bank

One of these elements Can't be detected by XRF1. Carbon2. Potassium3. Iron4. Calcium

XRD is a method used to identify substances due to: 1. chemical composition 2. <u>Structure</u> 3. Density **Device separate equal** λ of different elements in AAS 1. detector 2. nebulizer 3. hurner 4. <u>Monochometer</u>

A wave phenomenon in which the apparent bending & spreading of waves when they meet an obstruction 1. Reflection 2. Refraction 3. <u>Diffraction</u> 4. Interference

Minerals that slightly repelled by a magnetic field: 1. paramagnetic 2. diamagnetic 3. Ferromagnetic

Minerals that slightly attached by a magnetic field:1. paramagnetic2. diamagnetic3. ferromagnetic

Qz & Fs separated from minerals using

1. **bromoform** 2. lodoform 3. acetone 4. Ethanol

Staining for granites is done by using sodium cobaltnitrite, alkali-feldspar color changes into:1. Red2. Yellow3. White4. Orange

In X-ray tube anode made of these metals except:

1.Copper (Cu) 2.Tungsten (W) 3.Rhodium(Rh) 4. <u>Al</u> Hint. Heavy metal with high melting point <u>*Platinum, Tungsten*</u>

The standard thin section of rocks thickness1. 0.3mm2. 0.003mm3. 0.03mm4. 3.0mm

Materials containing a known concentration & usedto build calibration curve in instrument analysis1. Chemicals2. Buffer3. Standard4. Indicator

Method to distinguish between amorphous & crystalline silica? 2 techniques

- 1. **XRD**: can detect crystalline compounds \rightarrow SiO₂
- 2. **XRF**: amorphous (Si & O atoms concentration)

Before magnetic separation of minerals, sample are treated by hand magnet. Why? will clog the Frantz separator (instrument used to separate minerals)

Function of the crystal in Spectrometers of XRF?

عندما تصطدم ال primary X-ray بالعينة يخرج منها احد الالكترونات ويحل مكانه e من مستوى طاقة اعلى، وفرق الطاقة يُشَعُ على هيئة -x ray ويحل مكانه e من مستوى طاقة اعلى، وفرق الطاقة يُشَعُ على هيئة -x kr تسمى XRF ولان لكل عنصر له yare - معينة، اذا تم عكس λ للأشعة المنبعثة يحدث له تداخل وانعكاس عند θ معينة، اذا تم عكس هذه الاشعة مباشرة لل detector ستكون نسبة الخطأ كبيرة لذا يتم تمرير ها ل constant d spacing ستكون نسبة الخطأ كبيرة لذا يتم بحركة دائرية، وحركتها هذه تعمل على فصل ال ray-xlb المختلفة بحيث بحركة دائرية، وحركتها هذه تعمل على حدى (لانها تدور فعند كل θ بمحيط دورانها **تعكس \chi محدد** لعاصر محدد وعندما تتحرك تتغير θ فتعكس χ لعنصر اخر وباقي الأطول يحدث لها تداخل هدام...) How would you know that thin sections are still thick? <u>Using microscopic</u>

Give names of essential materials & machines needed to make thin section?

- 1. Glass slides, Cover slip, & Epoxy
- 2. <u>Diamond saw(cutting machine for rock slab)</u>
- 3. <u>Coarse, medium, & fine carbide grit powder</u> (400, 800, & 1200) to polished rock slab
- 4. Automatic grinding machine for polishing
- 5. Lap for grinding & a small warming plate
- 6. <u>Microscope (To ensure the accuracy)</u>
- 7. Hot plat (Electric gas)

What is the Diffraction: <u>wave phenomenon in which</u> the apparent bending & spreading of waves as they meet an obstruction, can be occurs with EMW such as light & radio waves, & in sound & water waves

What is the difference between coating & covering? The coating is just a thin cover on the sample to keep the details clear

Why minerals show several characteristics peaks on the diffractograph? <u>The diffracted beam (reflection)</u> from any set of lattice planes can only occur at particular angles (2θ) predicted by the Bragg law

Instruments used to distinguish among isotopes of an element <u>TIMSXRF, TIMS & SIMS</u>

Instrument used to distinguish ions of the same element in different valence states <u>wet chemical</u> <u>analysis or Mossbauer spectroscopy</u>

X ray cannot analysis atoms with atomic number Z < 11 why? Larger atoms have greater energy differences between orbitals (energy level more closely matches the energy of photon), & in Smaller the electron orbitals are separated by low jumps in energy, are less likely to absorb X-ray photons

SEM magnification 1000,000 times LM why? Because Resolution limited by λ (LM work with VL)

In contrast to visible light electron rays can give images with magnification up to 600.000X, why? Because it's works with x-ray λ

In SEM samples coated by gold, while for chemical analysis EPMA samples coated by carbon, Why?

الذهب اكثر قدرة لانتاج secondary ray لصنع صورةimaging يستخدم الكربون لانه خفيف (z<11) ولانه موصل للتيار الكهربائي ولو كان عنصر اثقل سيحدث له تحليل وليس للعينة

Difference between quantitative & qualitative analysis? Quantitative is the amount (concentration) of an atoms & qualitative is the type (e.g. Minerals, Crystals) of a given materials

important information

- XRD are used to identify crystalline substrate & XRF for noncrystalline substance
- In SEM samples coated by gold, & for chemical analysis in EPMA samples coated by carbon
- Diagram represents the interaction between radiation & λ
- Quantitative analysis (amount of an atoms): Microprobe analysis or Electron probe microanalyzer (EPMA), Atomic Absorption Spectroscopy (AAS), XRF
- Qualitative analysis (crystal structure): Atomic Absorption Spectroscopy (AAS), or XRD

WDS (Wavelength-	EDS (Energy-dispersive
dispersive	spectrometry)
spectrometry)	
By λ , using a diffracting crystal to isolate the characteristic X-ray peaks	By energy using a solid- state detector that discriminates between the energies of incoming photons
High spectral resolution (element clearly resolved) Higher peak/background (better detection limits) Sequential measurement of peaks, slower Specimen flat & in focus Delicate moving parts Expensive to buy متل ال XRF	Low spectral resolution (deconvolute overlapping peaks) Lower peak/background (lower precision) Simultaneous collection of whole spectrum, rapid Insensitive to specimen geometry No moving parts, & Less expensive الفرق بينه وبين WDS هو انه يعطي

Staining involves the use of 3 chemicals		
Hydrofluoric	To etch the polished surface,	
Acid (HF)	breaks bonds between K, Ca	
Amaranth	Powder to stain plagioclase	
C20H11N2Na3O10S3	on surface in a <mark>red</mark> color	
Sodium -	To stain any K-feldspar on	
Cobaltinitrite	that surface a yellow color	

Group	Definition		
	Have constant magnetic		
Ferromagnetic	properties, regardless they are		
	exposed to an external field		
Diamagnetic	don't have magnetic properties		
(Repelled)	unless it's exposed to an external		
Paramagnetic	field (repelled or attached to a		
(attached)	magnetic field)		
Group	Separated using		
Ferromagnetic	Hand-magnet		
Diamagnetic	FIMS to separate it from para. &		
	then using heavy liquids		
Paramagnetic	FIMS		

Common heavy liquids					
Bromoform				2.85 g/ml	
Tetrabromoethane			2.96 g/ml		
Diiodomethane			3.32 g/ml		
Granite Composition					
Para		I [A]	Dia	$\rho[g/cm^3]$	
Biotite		0.8	Feldspar,Qz	< 3.0	
Monazite		0.6	Apatite	3.1	
			Zircon	4.56	
0.4A	0.8 A		1.5A	1.5A	
Garnet	Biotit	e	Muscovite	Zircon	
Ilmenite	Hornblende		Spinel	Rutile	
Chromite	Hypersthene		Enstatite	Titanite	
Chloritoid	Chlorite		Tourmaline	Apatite	
Olivine	Augite		Zoisite	Corundum	
	Actinolite		Diopside	Barite	
	Staurolite		Tremolite	Fluorite	
	Epide	ote		Sillimanite	
				Kyanite	

Rays	Function		
Back-scattered	Different phases		
Secondary (SR)	External Morphology (Texture)		
	Imaging, & Zooming		
	High-resolution composition maps		
XRD	Crystal Structure (mineralogical)		
XRF	Chemical analysis (amorphous,		
	oxides, or elemental analysis)		
WDS	Such XRF (elemental analysis)		
EDS	Intensity at same time		
Electron probe	Quantitative: chemical analysis		
micro-analyzer	such as SEM but at small scales		
(EPMA)	Internal compositional structures		
Atomic	Elemental analysis such as XRF		
Absorption	Quantitative or Qualitative analysis		
Spectroscopy			
(AAS)			
Cathodolumi-	Internal structure		
nescence (VL)	(Gold coating)		
CL	Composition, lattice structure,		
	superimposed strain or damage		